

The size of the "process" indicates the minimum possible channel length.  
Magnitude of the electron charge in the channel [Q]:

$$|Q| = C_{OX}(WL)v_{OV}$$

$C_{OX}$  is the oxide capacitance, [F/m<sup>2</sup>]

$$C_{OX} = \frac{\epsilon_{OX}}{t_{OX}}$$

$\epsilon_{OX}$  is the permittivity of the SiO<sub>2</sub>.  
 $t_{OX}$  is the oxide thickness.  
For  $C_{OX}$  per micron squared, use  
 $C = C_{OX}WL$  [fF]

$$i_D = \left[ (\mu_n C_{OX}) \left( \frac{W}{L} \right) (v_{GS} - V_t) \right] v_{DS}$$

$$i_D = [g_{DS}] v_{DS}$$

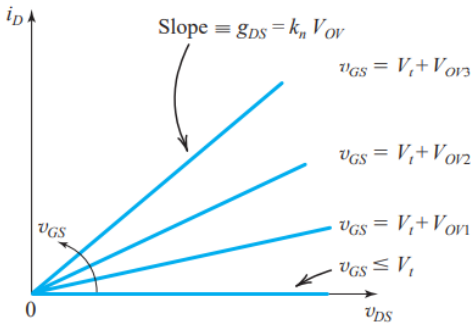
$$k'_n = \mu_n C_{OX}$$

$$k_n = k'_n (W/L)$$

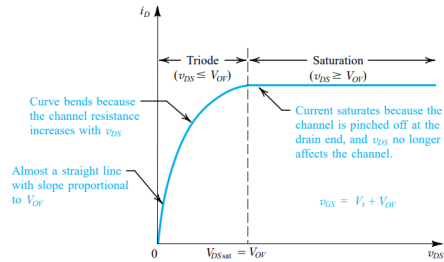
$k'_n$  is **process transconductance paramter**.  
 $k_n$  is **device transconductance paramter**.

When  $V_{DS}$  is small, the MOSFET behaves as a linear resistance  $r_{DS}$  whose value is controlled by the gate voltage  $v_{GS}$ .

$$r_{DS} = \frac{1}{g_{DS}}$$



Triode vs Saturation



Triode ( $v_{DS} \leq V_{OV}$ )

$$i_D = k'_n \left( \frac{W}{L} \right) \left( V_{OV} - \frac{1}{2} v_{DS} \right) v_{DS}$$

$$i_D = k'_n \left( \frac{W}{L} \right) \left[ (v_{GS} - V_t) v_{DS} - \frac{1}{2} v_{DS}^2 \right]$$

Saturation ( $v_{DS} \geq V_{OV}$ )

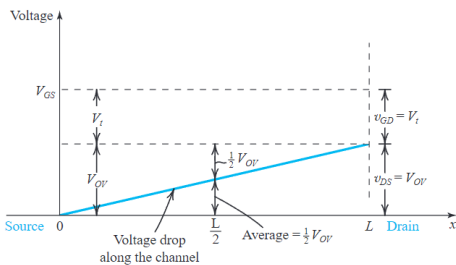
$$i_D = \frac{1}{2} k'_n \left( \frac{W}{L} \right) V_{OV}^2$$

$k_n = k'_n$ , so

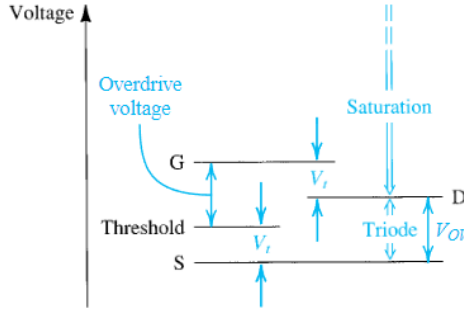
$$i_D = \frac{1}{2} k_n V_{OV}^2$$

Or,

$$i_D = \frac{1}{2} k_n (v_{GS} - V_{th})^2$$



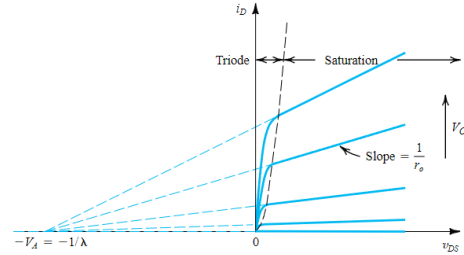
Constant  $V_{OV}$  can be replaced by variable  $v_{OV}$ .  
PMOS transistors operate similarly but the polarity is reversed, so  $v_{GS}$  must be negative and larger than a negative  $v_{tp}$ , as is  $v_{DS}$  negative.



If you care about **channel-length modulation**, then use the expression:

$$i_D = \frac{1}{2} k'_n \left( \frac{W}{L} \right) (v_{GS} - V_{th})^2 (1 + \lambda v_{DS})$$

$v_{DS} = -\frac{1}{\lambda} \mid V_A = \frac{1}{\lambda} \mid V_A = V'_A L$   
 $V_A$  (Early Voltage) has units of volts.  
 $V'_A$  has units of volts per micron.



Expression for  $r_o$ :

$$r_o = \frac{V_A}{I_D} = \frac{1}{\lambda I_D}$$

$I_D$  is the drain current without channel-length modulation taken into account.

$$I_D = \frac{1}{2} k'_n \frac{W}{L} (V_{GS} - V_{tn})^2$$

For a  $p$ -Channel MOSFET, everything is backwards, here is an equation showing the voltages without negative signs, everything here is considered in terms of positive voltages or magnitudes.

$$i_D = \frac{1}{2} k'_p \left( \frac{W}{L} \right) (v_{SG} - |V_{tp}|)^2 (1 + |\lambda| v_{SD})$$

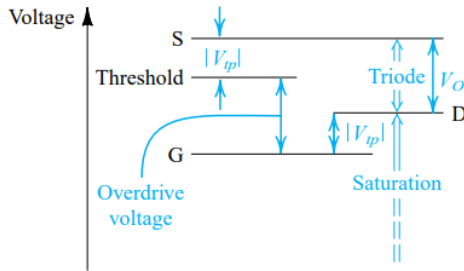
Also,

$$i_D = \frac{1}{2} k'_p \left( \frac{W}{L} \right) (v_{SG} - |V_{tp}|)^2 \left( 1 + \frac{v_{SD}}{|V_A|} \right)$$

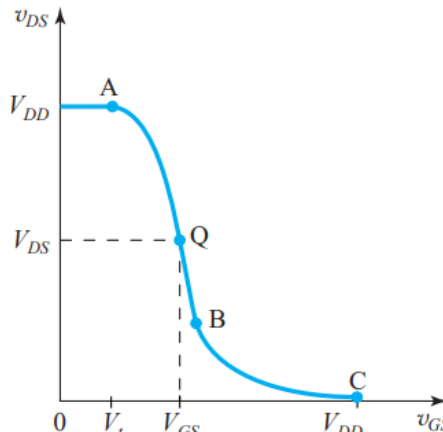
Kinda useful:

$$R_D = \frac{V_{DD} - V_D}{I_D}$$

$$R_D = V_{DD} - I_D R_D$$



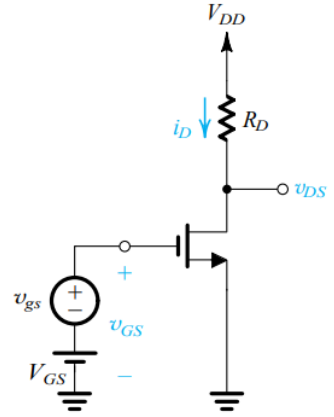
MOSFETs biased for linear amplification



Note **bias point Q**. Voltages  $V_{GS}$  and  $V_{DS}$  are related at the bias point by

$$v_{DS} = V_{DD} - \frac{1}{2} k_n R_D (v_{GS} - V_t)^2$$

$$v_{GS} = V_{GS} + v_{gs}$$



$A_v$  is expressed in terms of  $V_{OV}$  at the bias point by

$$A_v = -k_n V_{OV} R_D$$

$$A_v = -\frac{2I_D R_D}{V_{OV}} = -\frac{I_D R_D}{V_{OV}/2}$$

To prevent *nonlinear distortion*,  $v_{gs}$  must be sufficiently small.

$$v_{gs} \ll 2(V_{GS} - V_t)$$

$$v_{gs} \ll 2V_{OV}$$

When this condition is met, we can express  $i_D$  as:

$$i_D \simeq I_D + i_d$$

Of course,  $I_D = \frac{1}{2} k_n V_{OV}^2$   
and  $i_d = k_n (V_{GS} - V_t) v_{gs}$

$$g_m \equiv \frac{i_d}{v_{gs}} = k_n (V_{GS} - V_t)$$

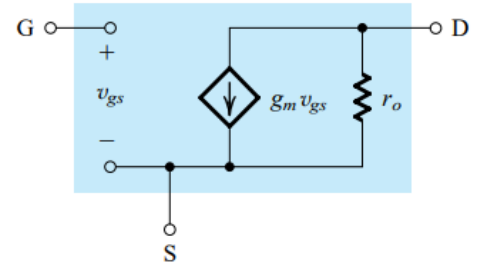
$$g_m = k_n V_{OV} = \mu_n C_{ox} \frac{W}{L} V_{OV}$$

$$g_m = k'_n (W/L) (V_{GS} - V_t) = k'_n (W/L) V_{OV}$$

$$g_m = \sqrt{2k'_n} \sqrt{W/L} \sqrt{I_D}$$

$$g_m = \frac{2I_D}{V_{GS} - V_t} = \frac{2I_D}{V_{OV}} = \sqrt{2\mu_n C_{ox} \frac{W}{L} I_D}$$

Small Signal Model



$$r_o = \frac{|V_A|}{I_D} = \frac{1}{\lambda I_D} \mid A_v = \frac{v_{ds}}{v_{gs}} = -g_m (R_D \parallel r_o)$$

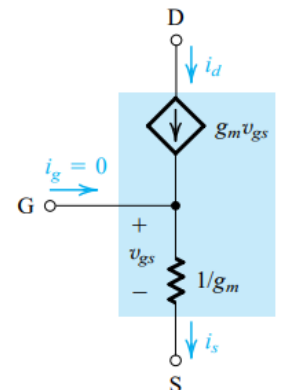
$$v_{DS} = V_{DD} - R_D i_D$$

$$v_{DS} = V_{DD} - R_D (I_D + i_d) = V_{DS} - R_D i_d$$

$$v_{DS} = -i_d R_D = -g_m v_{gs} R_D$$

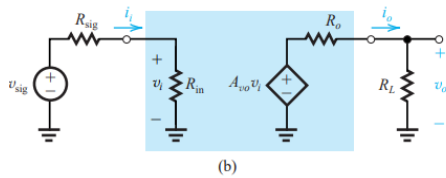
$$A_v \equiv \frac{v_{ds}}{v_{gs}} = -g_m R_D$$

T Equivalent-Circuit Model



$$i_d = i_s = g_m v_{gs}$$

## Characterizing Amplifiers

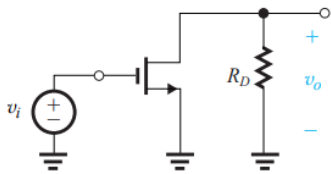


$$A_{vo} \equiv \frac{v_o}{v_i} \Big|_{R_L = \infty}$$

$$A_v \equiv \frac{v_o}{v_i} = A_{vo} \frac{R_L}{R_L + R_o}$$

$$G_v \equiv \frac{v_o}{v_{sig}}$$

## Basic circuit configurations



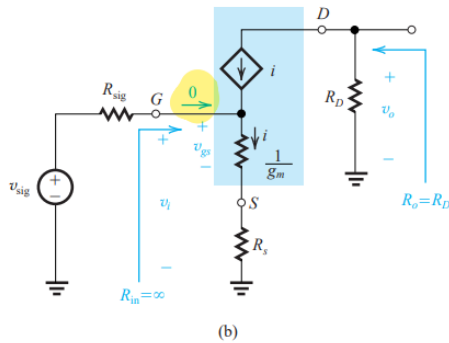
(a) Common Source (CS)

$$R_{in} = \infty \mid v_o = -(g_m v_{gs})(R_D \parallel r_o)$$

$$A_{vo} = -g_m(R_D \parallel r_o)$$

$$A_v = G_v = -g_m(R_D \parallel R_L \parallel r_o)$$

$v_{sig}$  must be much smaller than  $2V_{OV}$



$$v_{gs} = \frac{v_i}{1 + g_m R_s}$$

$$v_o = -i R_D$$

$$i = \frac{v_i}{1/g_m + R_s} = \left( \frac{g_m}{1 + g_m R_s} \right) v_i$$

Those two together make:

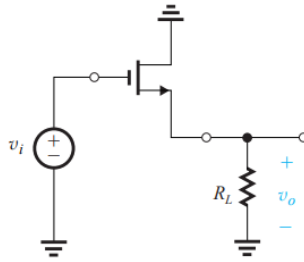
$$A_{vo} = \frac{v_o}{v_i} = -\frac{R_D}{1/g_m + R_s}$$

$$A_v = -\frac{R_D \parallel R_L}{1/g_m + R_s}$$

$$R_{in} = \frac{1}{g_m} \mid i = -\frac{v_i}{1/g_m} \mid v_o = -i R_D$$

$$A_{vo} \equiv \frac{v_o}{v_i} = g_m R_D$$

$$G_v = \frac{(R_D \parallel R_L)}{R_{sig} + 1/g_m}$$



(c) Common Drain (CD) / Source

Often used as a voltage buffer so that the signal isn't attenuated at the output.

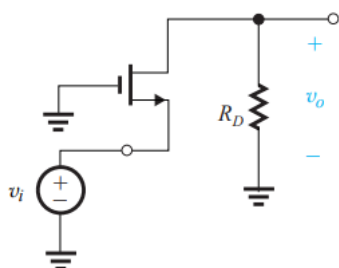
$$R_{in} = \infty \mid A_{vo} = 1 \mid R_o = 1/g_m$$

$$G_v = A_v = \frac{R_L}{R_L + 1/g_m}$$

## Biassing amplifier circuits

Fixing  $V_G$  and using  $R_s$ , use

$$V_G = V_{GS} + R_s I_D$$



(b) Common Gate (CG)